

**Search Notes**

Application/Control No.

10/692,773

Examiner

Eric B. Chen

Applicant(s)/Patent under  
Reexamination

LEE, HEON

Art Unit

1765

**SEARCHED**

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |

**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|   | DATE      | EXMR |
|---|-----------|------|
| EAST (all databases) (UPDATED) -<br>see search history printout   | 11/1/2005 | EC   |
| 216/3, 18, 22, 38, 39, 67, 104, 107, 109<br>438/692, 696, 710, 723-725, 745, 756,<br>757 (text search only) (UPDATED) | 11/1/2005 | EC   |
|   |           |      |
|   |           |      |
|   |           |      |
|   |           |      |
|   |           |      |
|   |           |      |
|   |           |      |
|   |           |      |
|   |           |      |